# Interoperability Week



Home

Meetings 2006

Logistics

Contact Us

#### The 2007 Event

NIST hosted the second annual Interoperability Week on April 23-25, 2007.

The conference's plenary session comprised three talks followed by a Q&A panel session:

## **Speakers/Panel Members:**

- Jason Matusow, Senior Director of Intellectual Property and Interoperability, Microsoft Corporation
- Eric Neumann, PhD, co-chair, W3C Healthcare and Life Sciences
- Ken Thibodeau, Electronic Records Archives Program Director, National Archives and Records Administration

# <u>Additional Panel Member (and Banquet Speaker)</u>:

David Prawel, President, Longview Advisors

# 2007 Meetings

For additional details, select a meeting or scroll down:

#### Meeting

3D and 2D Content Representation, Analysis, and Retrieval

Ontology Summit 2007

Metrology Interoperability

Plenary Session

**Banquet** 

Long Term Sustainment of Digital Information for Science and Engineering

ODVA EtherNet/IP Implementor Workshop #21

#### 3D and 2D Content Representation, Analysis, and Retrieval

Monday and Tuesday, April 23-24

Technical POC: Afzal Godil, Talapady Bhat, Anne Plant, NIST

This meeting is being organized to bring the research community together, increase communication among academia, industry, and government by creating a forum for the exchange of ideas, and to enhance transfer of technology. The workshop aims to define a research agenda for the future, and to define the types of resources(3D and 2D databases, evaluation methodologies, algorithms, and interoperability) that would be useful to stimulate more research n the field. The workshop is also to determine the type of role government can play to help stimulate this activity.



Meeting Web Site



# **Ontology Summit 2007**

Monday and Tuesday, April 23-24 Technical POC: <u>Steve Ray</u>, NIST

The challenge put before the ontology community this year is to clarify what everyone means when they use the term "ontology". Our objective is to define and agree to a systematic means of categorizing the many kinds of things that are referred to as "an ontology." By doing so, the research, development and Internet communities would have a better way of comparing, combining and mapping ontologies to one another (apples to apples). The range of what people call "ontologies" covers so-called "folksonomies", taxonomies, thesauri, conceptual models, and formal logic-based models to name just a few flavors. The Ontolog Forum plans to initiate a vigorous on-line discussion of promising strawman structures to characterize all of these possibilities, and more, culminating in a face-to-face meeting during NIST's Interoperability Week 2007 (scheduled for the week of April 23, 2007). Similar to last year's summit, the meeting will release a written communique to the international press, laying out the final categorization structure and locating some key ontologies within it.

#### **Metrology Interoperability**

Monday- Wednesday, April 23-25 Technical POC: <u>John Horst</u>, NIST

Metrology Interoperability consisted of two meetings:

Consortium of Consortia Planning Meeting for Metrology Interoperability

Date and Time: April 23, 2007

Meeting host: John Horst of NIST, john.horst@nist.gov, (301) 975-3430

Meeting summary: In response to the need for a more common vision worldwide in metrology interoperability, a proposal has been made to form a consortium of consortia, in other words, organize the existing groups worldwide working on metrology interoperability into a single consortia to provide structure and unity toward our common goal of component interoperability. A half-day session is planned to discuss and make plans for such an organization.



Presentations and minutes

• High-level Inspection Process Planning for Metrology Interoperability

Date and Time: April 24 - 25, 2007

Meeting host: John Horst of NIST, john.horst@nist.gov, (301) 975-3430

Meeting summary: At last year's International Metrology Interoperability Summit (IMIS), a call emerged to precisely define the information required to generate a high-level inspection process plan. The famous DMIS standard addresses lower level process plans for a CMM; however, there seems to be no single standard that correctly, completely, and unambiguously addresses the information needed to generate a high-level inspection process plan. Information contained in such a high-level plan is envisioned to be sufficient to drive any type of CMM: portable, fixed, contact, non-contact, scanning, etc.



Presentations and minutes

## Interoperability Week Plenary Session Tuesday, April 24, 9:00 - 10:30

The plenary will consist of three talks followed by a Q&A panel session.

#### Speakers/Panel Members:

 Jason Matusow, Senior Director of Intellectual Property and Interoperability for the Microsoft Corporation. In this role he focuses on a broad spectrum of issues including patent reform, copyright activism, indemnification, and the licensing of Microsoft's IP assets. Additionally, he is a leading strategist for Microsoft's global commitment to interoperability and has additional responsibility for the marketing and communications of Microsoft's software standards work.



• **Eric Neumann**, Senior Strategist for Teranode Corporation, a company developing next-generation systems for pharmaceutical companies. He is also founder and co-chair for the W3C Semantic Web Healthcare and Life Science Interest Group (HCLSIG) that is bringing together industry leaders to identify domain-specific applications that will benefit from semantic web technologies. He also has formed the Clinical Semantics Group, a consultancy group specializing in the development of intelligent applications for clinical trials informatics. Prior to this, Dr. Neumann was Global Head of Knowledge Management for Scientific and Medical Affairs within Sanofi-Aventis, covering all of global R&D. He has also developed the first Drug Discovery semantic web dashboard called BioDash. He has also held executive positions at Beyond Genomics, 3rd Millenium, and Netgenics, and was an NSF-funded researcher for 6 years while at and Bolt, Beranek, and Newman. Dr. Neumann is an expert in knowledge-based methods for the pharmaceutical industry, and has been in the biotechnology industries for the past 16 years.

Dr. Neumann holds an undergraduate degree from the Massachusetts Institute of Technology, and a PhD in neurobiology and developmental genetics from Case Western Reserve University.

• **Ken Thibodeau**, Director of the Electronic Records Archives (ERA) Program at the National Archives and Records Administration (NARA). ERA is NARA's strategic initiative to build a virtual archives capable of preserving all types of electronic records and delivering them to future generations of users on future generations of technology. Dr. Thibodeau has 30 years experience in archives and records management, and is an internationally recognized expert in electronic records. He has served as Chief of the Records Management Branch of the National Institutes of Health, Director of the Center for Electronic Records at NARA, and Director of the Department of Defense Records Management Task Force. He earned a Ph.D. in the history and sociology of science from the University of Pennsylvania, and held several post doctoral fellowships in computer science. He has been a visiting professor and lecturer at universities in the U.S., Canada, France, Germany, Italy, and the U.K. A Fellow of the Society of American Archivists, he has published over 30 papers and spoken at more than 150 conferences around the world.

#### Additional Panel Member (and Banquet Speaker):

• David Prawel, President, Longview Advisors (See "Banquet Dinner" entry below for bio.)

Barbara Cuthill provided a presentation on NIST's Advanced Technology Program.

# **Banquet Dinner** Tuesday, April 24, 7:00 PM

The featured speaker was **David Prawel**, founder and president at Longview Advisors Inc., a consulting firm serving the manufacturing industry. He has enjoyed more than 25 years in the 3D software industry. As a consultant, speaker, author, and entrepreneur, he provides insight and advice about 3D technology to dozens of manufacturers and software companies around the world..

# Long Term Sustainment of Digital Information for Science and Engineering: Putting the Pieces Together

Tuesday - Wednesday, April 24-25

Technical POC: <u>Josh Lubell</u> and <u>Rachuri Sudarsan</u>, NIST

Researchers at universities, in industry, and in government are developing tools and standards for archiving and preserving the ever-increasing volume of digital information humankind produces. Meanwhile, records managers are grappling with maintaining their organizations' data assets and responding to requests for electronic information from regulators, legal investigations, and other sources. Scientists and engineers, in addition to the aforementioned issues, want the digital models and systems they build today to be extensible and reusable for subsequent generations of technologists. Our discussion, a sequel to last year's highly successful Long Term Knowledge Retention workshop, will focus on policies of digital preservation and applying promising technologies to solve preservation problems in product design, engineering, and manufacturing in particular, with possible extensions to include chemistry, biology, and other disciplines where critical information must be "future-proofed."

#### **Tuesday April 24**

Welcome

Bill Regli, Drexel University, <u>Preservation of Engineering Artifacts</u>
Chris McMahon, University of Bath, <u>From knowledge management to digital curation - a UK report and perspective</u>

Mike Smorul, University of Maryland, <u>ADAPT: An Approach to Digital Archiving and Preservation Technology</u> Kate Zwaard, US Government Printing Office, <u>FDsys Update NIST April 07</u>
Prepare for Breakouts: <u>LTKR Workshop Points</u> and <u>LTKR workshop.mm</u> (a FreeMind mind map). (<u>See this site for FreeMind software</u>.)

#### **Wednesday April 25**

Report from Breakout Group 1, plus a FreeMind mind map. (See this site for FreeMind software.)
Report from Breakout Group 2

## ODVA EtherNet/IP Implementor Workshop #21

Tuesday- Wednesday, April 24-25 Technical POC: <u>Jim Gilsinn</u>, NIST

The workshop will provide the following benefits to vendors implementing EtherNet/IP on products:

- Educate product developers on EtherNet/IP and Industrial Ethernet technologies
- · Provide a collaborative forum for developers to discuss common issues and solutions
- Promote EtherNet/IP device interoperability through product design recommendations and an interoperability validation event (PlugFest)

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